

You live it. We measure it. Life, tested by Advantest.



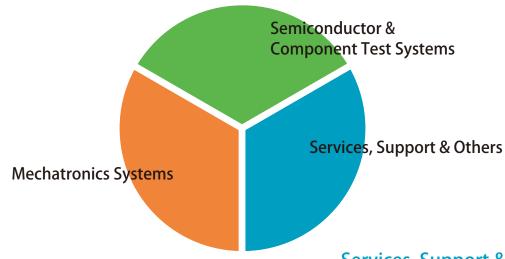
Business Segments

Technology Support on the Leading Edge

Since 1954, Advantest's measurement technologies have contributed to the safety and security of end users around the globe. To provide the advanced solutions and services that meet the needs of our customers, we strive continuously to improve. Our commitment to ongoing innovation keeps us on the leading edge of technological progress.

Semiconductor and Component Test Systems

Advantest provides test systems that are used to assure the quality of diverse semiconductors utilized in smartphones, PCs, automobiles, and many other electronic products we use every day.



Mechatronics Systems

Advantest's mechatronics products support our customers in the semiconductor industry across a broad range of needs.

Our test handlers and device interfaces are essential to efficient test processes, while our nanotechnology products, including wafer / mask measurement tools and lithography systems, contribute to leading-edge device development.

Services, Support & Others

From installation and maintenance to high-added-value solutions, such as applications that maximize utilization rates, Advantest's global service and support network helps our customers to get the most out of our products. In our New Business Segments, our measurement technologies are finding new applications, and opening up new markets with ground-breaking products.

Semiconductor & Component Test Systems

Semiconductor Test Systems

Advantest's test systems input signals to the semiconductor and measure their output signals to determine whether the semiconductors are good or defective. Providing productivity gains and broad coverage of various devices, Advantest's test technology is highly valued by customers around the world, whose support has brought the company a globally dominant market position.

SoC Test Systems

These test systems employ modular configurations so that their performance boards can easily be exchanged to flexibly support the requirements of testing diverse SoC devices, such as micro-processors, applications processors, communications ICs, power management ICs, and others.

Advantest also supplies test systems for display driver ICs, which control the displays of smartphones, flat-screen televisions, and other products. With a worldwide installed base of more than 1,500 units, our display driver IC test systems are the global standard in this market.

Memory Test Systems

Our memory test systems contribute to customer productivity by testing DRAM, NAND, and other memory devices with high-quality, high-speed, highly parallel capabilities unmatched in the sector.











EVA

Advantest's groundbreaking new Evolutionary Value Added Measurement System (EVA) provides all-in-one support for analog IC, sensor, mixed signal IC, and other semiconductor devices, from R&D through to volume production. EVA's superior measurement precision and system scalability, and an intuitive user interface that does not require the use of programming languages, make it a measurement system that combines the benefits of a semiconductor test system and an electronic measurement instrument.



EVA100

Burn-In Systems

Burn-in systems apply thermal and electrical stress to semiconductors, screening out faulty devices at an early stage in the manufacturing process.



B6700

Mechatronics Systems

Test handlers

Handlers deliver packaged devices to test systems at high speed, and automatically sort them into pass / fail trays based on test results. Advantest's handlers also provide precision placement control and manage the temperature requirements of devices under test at high speed and with great precision, which enables the handling of extremely small devices with stringent requirements for contact placement and temperature management.





M6245 (>)

M4871 (>)

Device Interfaces

LINK (>)

Semiconductors differ in size, shape and specification, requiring specialized device interfaces when being tested. Advantest's DI products connect devices to test systems electronically and mechanically, with industry-leading precision. Expert teams around the world can provide support for a diverse range of devices, contributing to swift customer device production ramps.



Probe Card ()



Change Kit (>)

MVM-SEM®

LINK (>)

Utilizing electron beams, Advantest's scanning electron microscopes measure circuit patterns on wafers and photomasks, providing real-time data on width, height, and side-wall measurement. Based on proprietary technology, these MVM-SEM (Multi Vision Metrology Scanning Electron Microscope) tools are steadily increasing their market following, thanks to their unique level of support for extremely small and 3D devices.





E3310 ()

E3640 (>)

*MVM-SEM® = Multi Vision Metrology Scanning Electron Microscope

** MVM-SEM is either a registered trademark or a trademark of Advantest Corporation in Japan, the United States and other countries.

■ EB Lithography Systems

LINK (>)

Advantest's EB lithography tools also utilize electron beams to etch circuit patterns directly on substrates such as wafers with the nanoscale precision required at the 1Xnm node. Amid growing challenges for traditional nanoscale lithography methods, EB lithography is gaining attention for its ability to support the most advanced nanoscale processes.



F7000 (>)

Test Cells

Advantest has long been the industry's only ATE provider to design and manufacture its own fully integrated suite of production test-cell solutions comprised of testers, handlers, device interfaces, and software. These components assure the industry's highest levels of test quality and sufficiency, and have been widely adopted by global customers.



Test system mainframe

Services, Support & Others

New Businesses

Targeting a new level of sustainable growth, Advantest is incubating a range of new businesses. These groundbreaking enterprises build seamlessly on our amassed measurement technology, offering innovative solutions for measurement scenarios that have not been addressable with existing technology.

LINK (>)

Terahertz Spectroscopy and Imaging Analysis Systems

Utilizing terahertz waves, Advantest's terahertz systems enable non-destructive analysis of samples that cannot be analyzed with existing technologies such as ultrasound and infrared. They offer a new evaluation solution for diverse applications, including pharmaceutical coating thickness and tablet density measurement, and

TAS7500 Series (>)

■ Mobile System Level Test

W2BI, Inc. is a member of the Advantest Group offering wireless device test automation products for the world's top mobile operators and suppliers. Our system level test solutions ensure interoperability across regions and carriers, assisting customers worldwide to sig-

nificantly improve their device quality and time-to-market.

> Click to view a video introducing W2BI.

■ Hadatomo™ Photoacoustic Microscope

Combining the benefits of optical and ultrasound measurement, this new photoacoustic microscope non-destructively images blood vessels within the dermis to a depth of 3mm—without the use of contrast agents—a feat impossible with existing technologies. It offers new insights to researchers and practitioners in dermatology and regenerative medicine.

Hadatomo™ WEL5100 (>)

Launched sales of 3D analysis systems utilizing terahertz technology 2010

analysis of failures in electronic

circuits.

2013

Entered the mobile system level test business

2015

Launched sales of the Hadatomo™

Launched Cloud Testing Service, Inc. 2012

Launched sales of SSD test system 2014 Launched sales of the AirLogger™

LINK (>)

■ CloudTesting[™] Service*

This on-demand test service, offered by Advantest subsidiary Cloud Testing Service, Inc., gives customers the ability to download test software from the cloud and run it on our compact test terminals (available for lease). CTS's unique monthly fee structure brings world-class test IP within easy reach, making the service optimal for educators and researchers

CloudTesting™ Station (>)

SSD Test Systems

Advantest's SSD test systems offer system-level test of solid state drives, which are used in high-end data servers for enterprise memory storage, and client storage solutions, which are becoming a key technology for the IoT era.



MPT3000 (>)

■ AirLogger[™]

This unique data logger measures temperatures at multiple points and transmits measurements wirelessly, massively improving efficiency by doing away with cabling. It also enables easy measurement of temperatures in small, enclosed

spaces and rotating objects such as wheels.



AirLogger™ temperature measurement unit. (>)



Measurement of temperature of a rotating object.